

Effect of Oxygen Content in Silicon Suboxide Nanoparticles on UV Radiation Shielding

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Introduction

Information about UV radiation

- ✓ Exposure from UV causes harmful damages to human health
- ✓ UVA (315-400 nm) and UVB (280-315 nm) rays reach the ground surface unlike UVC (100-280 nm)

Non-stoichiometric silicon suboxide (SiO_x , $0 < x < 2$)

- ✓ A promising oxide material due to its high chemical stability and good mechanical properties^[1]
- ✓ Widely applied to semiconductors and optical coatings thanks to the outstanding optical properties of SiO_x
- ✓ The inherent properties can be maximized if SiO_x forms nanostructures
- SiO_x nanoparticles: A good candidate for UV shielding

Effects on optical property depending on oxygen content

- ✓ Oxygen content is expressed as the oxidation state of a material
- ✓ Different oxidation state means a different chemical state
- Resulting in changes in UV absorption or wavelength range

Focus of research

- ✓ Showing the UV shielding characteristic of SiO_x nanoparticles
- ✓ Confirming the optical change depending on oxygen content

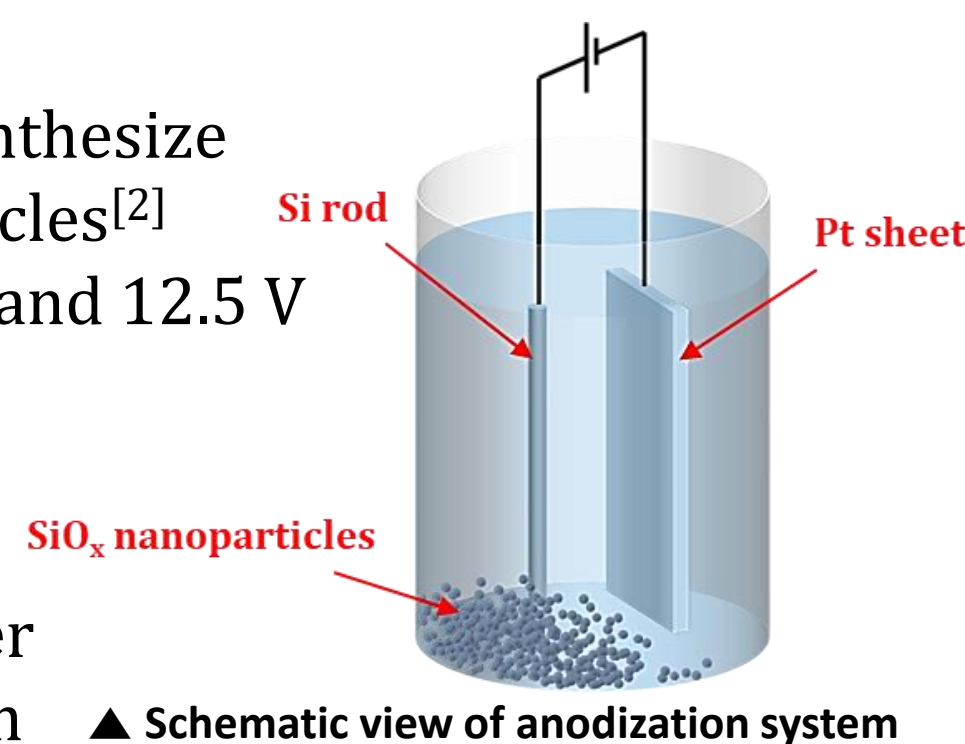
Materials & Methods

Materials

- ✓ Working electrode: P-type Si wafer (<100>, B-doped, 0.001-0.003 Ω cm)
- ✓ Counter electrode: Pt sheet (10 mm \times 40 mm \times 0.5 mm)
- ✓ Electrolyte: 10 M NH_4F aqueous solution

Sample preparation

- ✓ Anodization: Easy route to synthesize diverse metal oxide nanoparticles^[2]
- ✓ Applied voltage: DC 7.5, 10.0, and 12.5 V
- ✓ Reaction time: 1 hr
- ✓ Anodization temperature: 5°C using a thermostat
- ✓ Rinsing particles with DI water & filtering them under vacuum



Sample characterization

- ✓ FESEM: Magellan400, FEI, USA
- ✓ XPS: K-alpha, Thermo VG Scientific, USA → Al $K\alpha$ radiation
- ✓ UV-Vis: Lambda 1050, Perkin Elmer, USA

Oxygen content of SiO_x nanoparticles

- ✓ Five oxidation state of a Si atom: 0, +1, +2, +3, and +4
- Si-(Si_4), Si-(Si_3O), Si-(Si_2O_2), Si-(SiO_3), and Si-(O_4)
- Randomly combined each other to form amorphous phase
- Random bonding model for SiO_x
- ✓ Different binding energy depending on each oxidation state
- Si-(Si_4) has two values of binding energy due to spin-orbital splitting^[3]

▼ Oxidation number of Si and binding energy depending on oxidation state

Oxidation number	Tetragonal structure	Chemical structure	Binding energy (eV)
0	Si-(Si_4)	Si	98.9/99.5
1	Si-(Si_3O)	Si_2O	100.0
2	Si-(Si_2O_2)	SiO	101.0
3	Si-(SiO_3)	Si_2O_3	102.0
4	Si-(O_4)	SiO_2	103.1

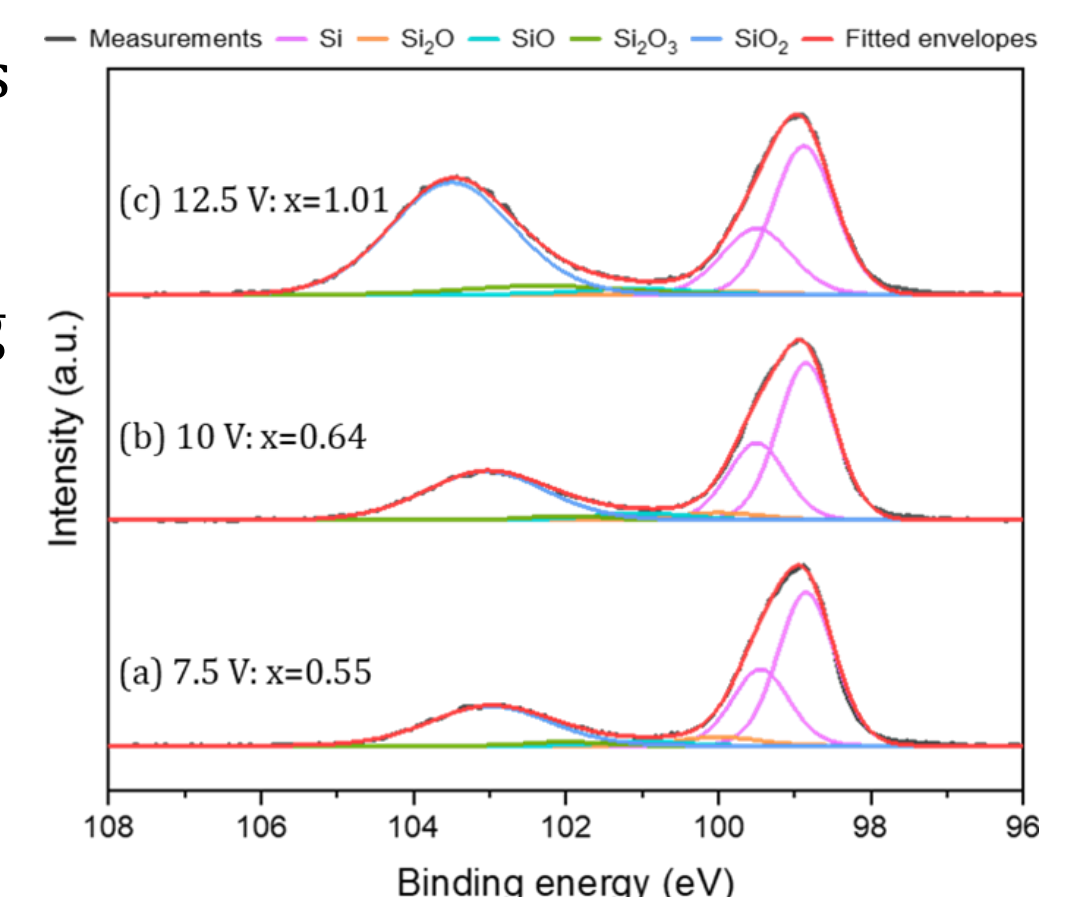
- ✓ Oxygen content of SiO_x (i.e., x-value) can be calculated using the information of five oxidation state

$$\rightarrow x = \frac{0.0 \times a + 0.5 \times b + 1.0 \times c + 1.5 \times d + 2.0 \times e}{a + b + c + d + e}$$

a, b, c, d, and e: Peak area of each oxidation number (0 to 4) in XPS spectrum

- ✓ X-value of SiO_x increases as applied voltage increases
- More O^{2-} ions react with Si which are produced during anodization

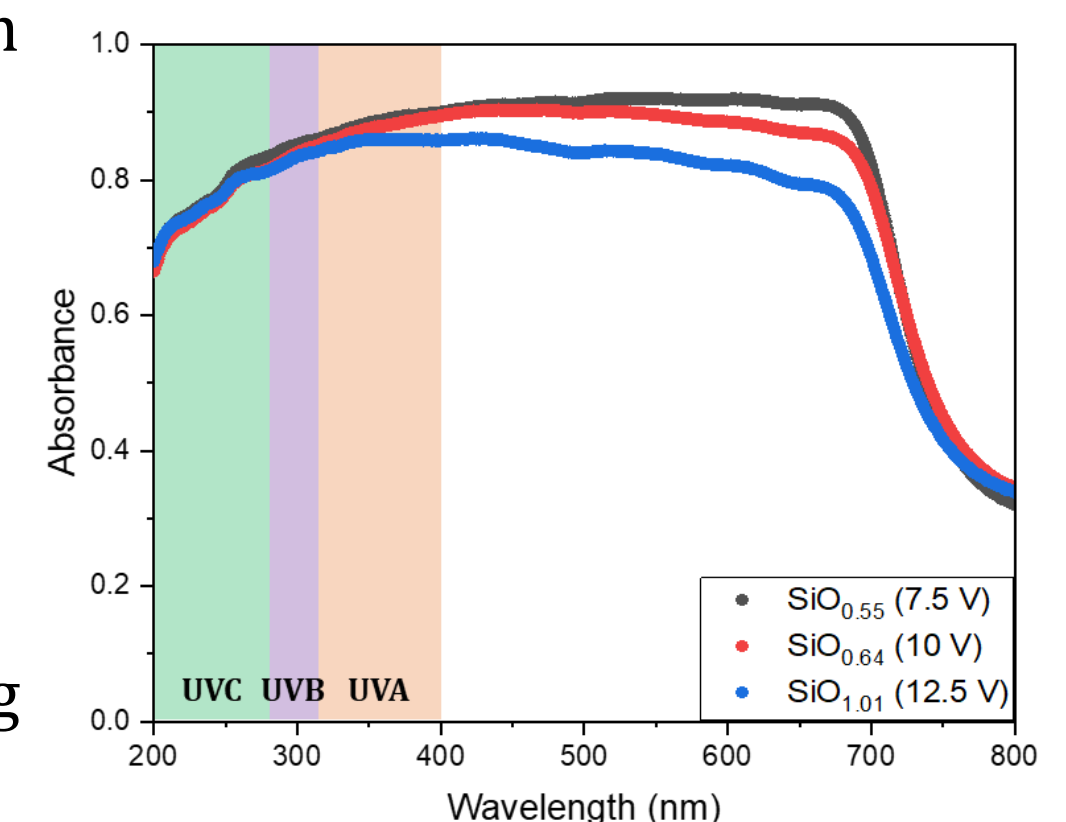
- ✓ SiO_x nanoparticles with different oxygen content were obtained
- $\text{SiO}_{0.55}$, $\text{SiO}_{0.64}$, and $\text{SiO}_{1.01}$



▲ XPS Si 2p spectra of SiO_x nanoparticles synthesized at each anodization voltage and calculated x-values after peak deconvolution

UV absorption analysis

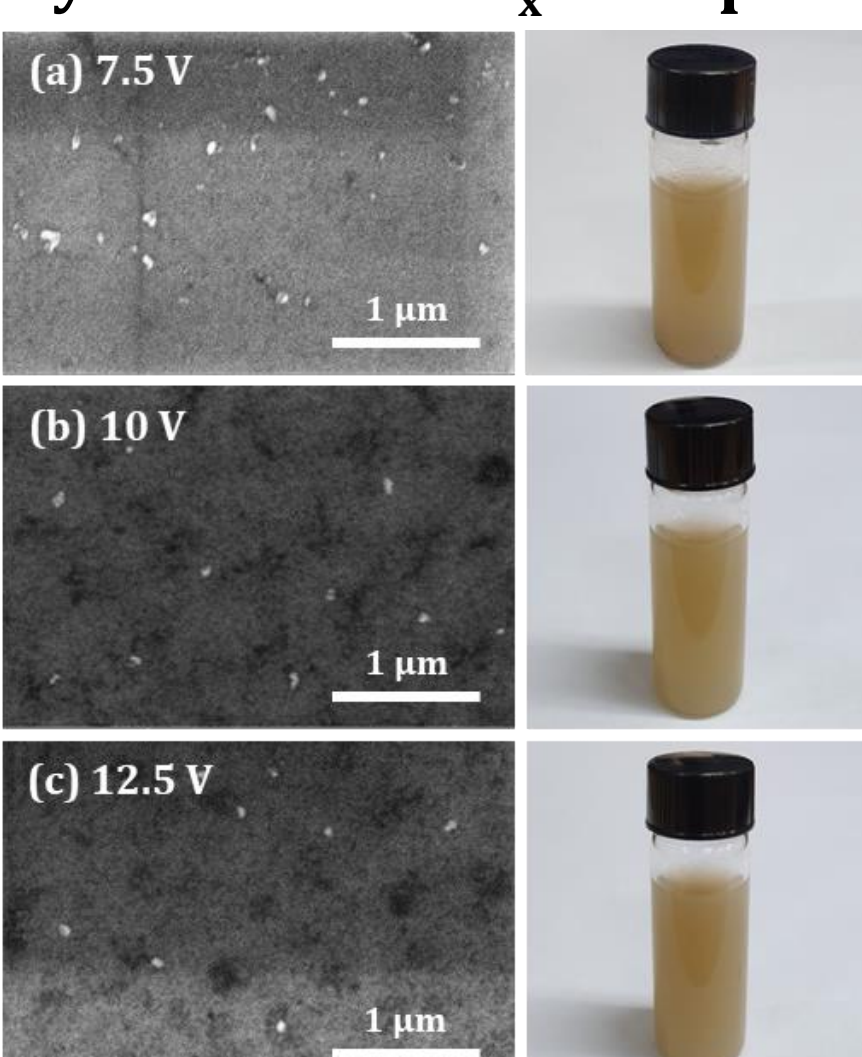
- ✓ Absorbance = $\log \frac{I_0}{I}$
- I_0 : Initial intensity of wave
- I : Intensity after absorption
- ✓ ~85% of UVA and UVB are absorbed by various SiO_x nanoparticles
- Slightly higher absorbance at lower oxygen content
- The number of oxygen vacancies increases as the x-value decreases, resulting in reduction in band gap
- The lower optical band gap, the greater UV absorption^[4]



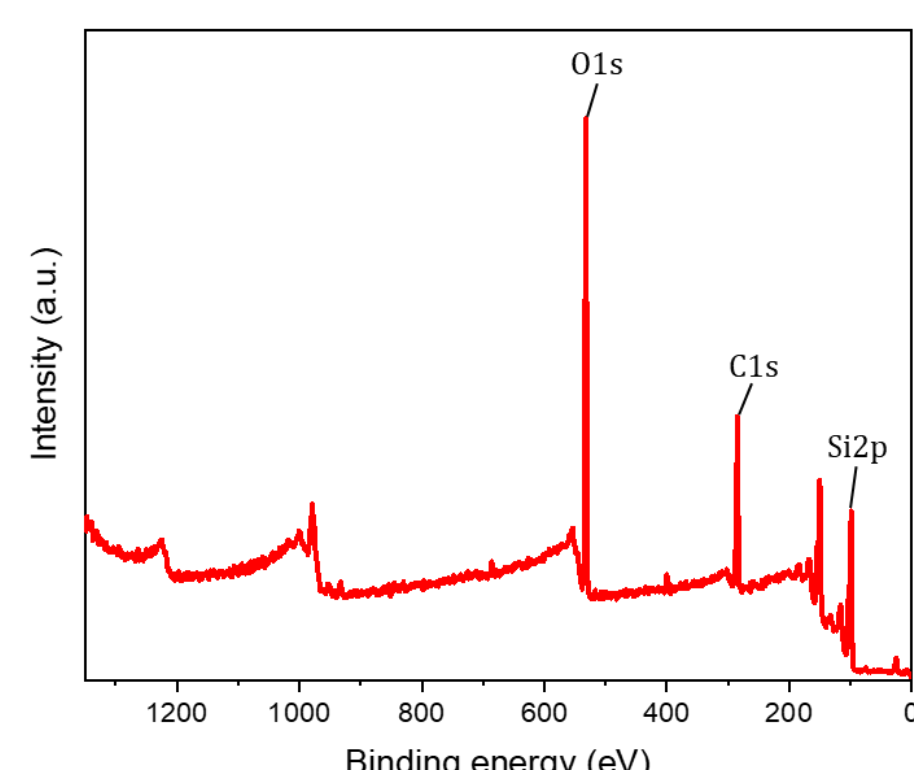
▲ UV/Vis photon absorbance of $\text{SiO}_{0.55}$, $\text{SiO}_{0.64}$, and $\text{SiO}_{1.01}$ nanoparticles

Results & Discussion

Synthesis of SiO_x nanoparticles



- ✓ Average diameter: 62.9, 66.3, and 73.6 nm each for 7.5, 10.0, 12.5 V
- ✓ Main elements: Si and O → SiO_x



▲ XPS element survey of SiO_x nanoparticles synthesized at 7.5 V.

▲ FESEM images and digital photographs of SiO_x nanoparticles synthesized at each anodization voltage: (a) 7.5, (b) 10.0, and (c) 12.5 V.

Conclusions

- 85% of UVA and UVB rays are absorbed by SiO_x nanoparticles prepared by anodization due to outstanding optical property
- SiO_x nanoparticles with lower oxygen content have higher UV absorption characteristic because of a lower optical band gap resulting from more oxygen vacancies

Acknowledgement

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